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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO
10/664,782	09/16/2003	Christophe Maleville	4717-6600	4834
28765 7	590 02/11/2005		EXAMINER	
WINSTON & STRAWN			JACKSON, ANDRE K	
PATENT DEP			ADTIBUT	DADED MINORD
1400 L STREE	ET, N.W.		ART UNIT	PAPER NUMBER
WASHINGTO	N, DC 20005-3502		2856	
			DATE MAILED: 02/11/2009	5

Please find below and/or attached an Office communication concerning this application or proceeding.

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	Application No.	Applicant(s)				
	10/664,782	MALEVILLE, CHRIS	STOPHE			
Office Action Summary	Examiner	Art Unit				
	André K. Jackson	2856				
The MAILING DATE of this communication a	ppears on the cover sheet w	vith the correspondence add	ress			
Period for Reply	N V IO CET TO EVOIDE A N	ACNITU(C) EDOM				
A SHORTENED STATUTORY PERIOD FOR REF THE MAILING DATE OF THIS COMMUNICATION - Extensions of time may be available under the provisions of 37 CFR after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a r - If NO period for reply is specified above, the maximum statutory period. - Failure to reply within the set or extended period for reply will, by state Any reply received by the Office later than three months after the material earned patent term adjustment. See 37 CFR 1.704(b).	N. 1.136(a). In no event, however, may a eply within the statutory minimum of this od will apply and will expire SIX (6) MO oute, cause the application to become A	reply be timely filed frty (30) days will be considered timely. NTHS from the mailing date of this considered timely. BANDONED (35 U.S.C. § 133).				
Status						
1) Responsive to communication(s) filed on	·					
2a) This action is FINAL . 2b) ⊠ TI	nis action is non-final.					
3) Since this application is in condition for allow	Since this application is in condition for allowance except for formal matters, prosecution as to the merits is					
closed in accordance with the practice under	r <i>Ex parte Quayl</i> e, 1935 C.I	D. 11, 453 O.G. 213.				
Disposition of Claims						
4) Claim(s) 1-21 is/are pending in the application	on.					
4a) Of the above claim(s) is/are withdrawn from consideration.						
5) Claim(s) is/are allowed.						
6)⊠ Claim(s) <u>1,2,16 and 20</u> is/are rejected.	•					
')⊠ Claim(s) <u>3-15,17-19 and 21</u> is/are objected to.						
8) Claim(s) are subject to restriction and	l/or election requirement.					
Application Papers						
9) The specification is objected to by the Exami	ner.					
10) The drawing(s) filed on is/are: a) a	ccepted or b) objected to	by the Examiner.				
Applicant may not request that any objection to the	ne drawing(s) be held in abeya	nce. See 37 CFR 1.85(a).				
Replacement drawing sheet(s) including the corre	•		• •			
11) The oath or declaration is objected to by the	Examiner. Note the attache	d Office Action or form PTC)-152 .			
Priority under 35 U.S.C. § 119						
12) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of: 1. Certified copies of the priority docume 2. Certified copies of the priority docume 3. Copies of the certified copies of the prapplication from the International Bure * See the attached detailed Office action for a li	ents have been received. Ents have been received in Amount of the interior in	Application No n received in this National S	Stage			
Attachment(s)						
1) Notice of References Cited (PTO-892)	4) Interview	Summary (PTO-413)				
2) Notice of Draftsperson's Patent Drawing Review (PTO-948)	Paper No.	(s)/Mail Date	152)			
 Information Disclosure Statement(s) (PTO-1449 or PTO/SB/(Paper No(s)/Mail Date 	6) Other:	Informal Patent Application (PTO-	132)			

DETAILED ACTION

Claim Rejections - 35 USC § 103

- 1. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 2. Claims 1,2,16 and 20 are rejected under 35 U.S.C. 103(a) as being unpatentable over Lindahl et al. in view of Brown.

Regarding claim 1, Lindahl et al. disclose in the patent entitled "Determining cleanness of air in a controlled environment" exposing a test surface of a test substrate to the atmosphere for a test time to capture an amount of particles and analyzing the amount of captured particles (Column1, lines 70-72; Column 2, lines 3-19). Lindahl does not disclose comparing the analyzed amount of particles with a reference amount of particles from a reference substrate to determine the particle concentration in the environment. However, Brown discloses in the patent entitled "Method and apparatus for investigating surfaces" comparing the analyzed amount of particles with a reference amount of particles from a reference substrate to determine the particle concentration in the

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environment (Abstract). Therefore, it would have been obvious to one of ordinary skill in the art at the time the invention was made to modify Lindahl to include comparing the analyzed amount of particles with a reference amount of particles from a reference substrate to determine the particle concentration in the environment. By adding this feature the user would be able to determine the amount of particles collected on a substrate being tested.

Regarding claim 2, both Lindahl and Brown disclose that it is known to clean at least the test surface of the test substrate prior to exposing it to the atmosphere (Column 1, lines 64-65 and Column 1, line 15).

Regarding claim 16, both Lindahl and Brown disclose that it is known to clean at least the substrate prior to exposing it to the atmosphere to provide an essentially particle-free reference (Column 1, lines 64-65 and Column 1, line 15).

3. Regarding claim 20, Lindahl do not disclose analyzing a particle concentration of the reference substrate. However, Brown discloses analyzing a particle concentration of the reference substrate (Column 1, lines 45-63). Therefore, it would have been obvious to one of ordinary skill in the art at the time the invention was made to modify Lindahl to include analyzing a particle concentration of the reference substrate. By adding this feature the user would be able to precisely measure the particles on the test substrate.

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- 4. Claims 3-15,17-19 and 21 are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.
- 5. Any inquiry concerning this communication or earlier communications from the examiner should be directed to André K. Jackson whose telephone number is (571) 272-2196. The examiner can normally be reached on Mon.-Thurs. 7AM-4PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Hezron Williams can be reached on (571) 272-2208. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

A.J.

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February 3, 2005

HEZRON WILLIAMS

SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2800